.

Measurement Report for Device, , , UID 0 -, Channel 0 (2450.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, **HSL**	,		CW, 0--	2450.000, 0	7.85	1.87	39.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - xxxx	HBBL-600-10000 Charge:xxxx, 2024-May-16	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16, 17:05	2024-05-16, 17:13
psSAR1g [W/kg]	5.02	5.41
psSAR10g [W/kg]	2.38	2.41
Power Drift [dB]	0.04	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)